

PH6325L N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK Rev. 2 — 22 December 2011 Product

Product data sheet

Product profile 1.

1.1 General description

Logic level N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOSTM technology

1.2 Features and benefits

- Low thermal resistance
- Low threshold voltage

- Optimized for use in DC-to-DC converters
- Very low switching and conduction losses

1.3 Applications

- DC-to-DC convertors
- Notebook computers

1.4 Quick reference data

- Switched-mode power supplies
- Voltage regulators

Table 1.	Quick reference data					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	25	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	78.7	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Static cha	racteristics					
R _{DSon}	drain-source on-state resistance	V_{GS} = 4.5 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	7.4	9.5	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	4.7	6.3	mΩ
Dynamic	characteristics					
Q_{GD}	gate-drain charge	V_{GS} = 4.5 V; I_{D} = 25 A; V_{DS} = 12 V; see	-	3.3	-	nC
Q _{G(tot)}	total gate charge	Figure 11; see Figure 12	-	13.3	-	nC



2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		-
2	S	source	mb	
3	S	source		
4	G	gate		
mb	D	mounting base; connected to drain	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	mbb076 S
			SOT669 (LFPAK; Power-SO8)	

3. Ordering information

Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
PH6325L	LFPAK; Power-SO8	plastic single-ended surface-mounted package; 4 leads	SOT669	

Limiting values 4.

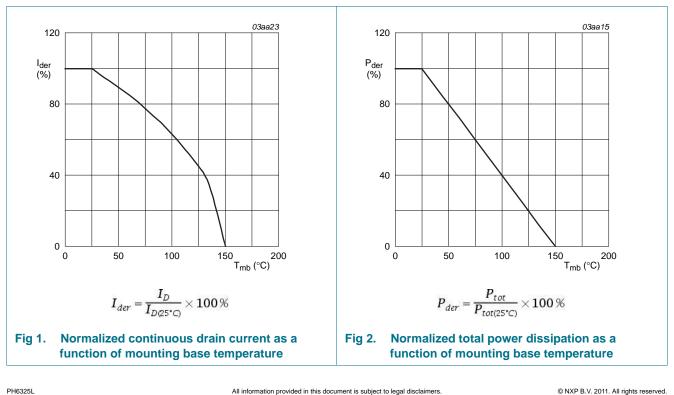
Limiting values Table 4.

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	25	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	49.6	А
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1;</u> see <u>Figure 3</u>	-	78.7	А
I _{DM}	peak drain current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	236	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dr	ain diode				
I _S	source current	T _{mb} = 25 °C	-	52	А
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	208	А
Avalanche	e ruggedness				
E _{DS(AL)R}	repetitive drain-source avalanche energy	t_p = 0.015 ms; unclamped; R _{GS} = 50 Ω; I _D = 3.4 A; [1][2] V _{DD} = 25 V; V _{GS} = 10 V	-	1.2	mJ
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 34 A; V_{DD} = 25 V; t_p = 0.15 ms; unclamped; R_{GS} = 50 Ω	-	115	mJ
-					

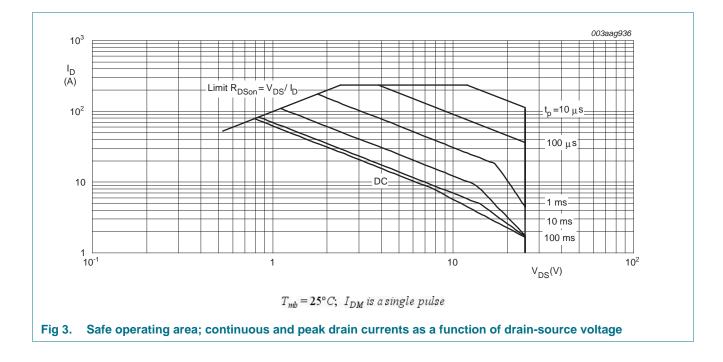
[1] Duty cycle is limited by the maximum junction temperature.

Repetitive avalanche failure is not determined simply by thermal effects. Repetitive avalanche transients should only be applied for short [2] bursts, not every switching cycle.



All information provided in this document is subject to legal disclaimers.

N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK

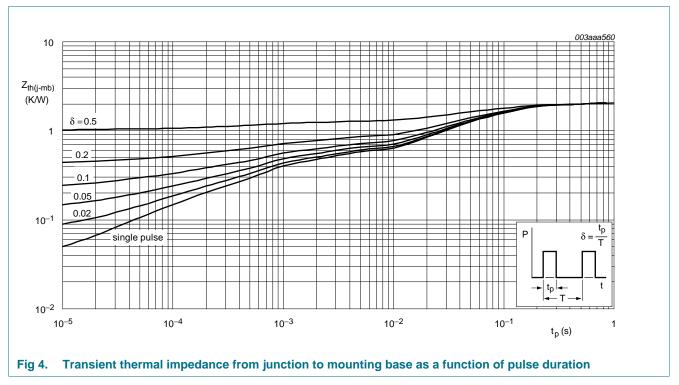


PH6325L

N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK

5. Thermal characteristics

SymbolParameterConditionsMinTypMaxReferencethermal resistance from junction to mounting basesee Figure 42						
Region thermal resistance from junction to mounting base see Figure 4	p Max Unit	Тур	Min	Conditions	Parameter	Symbol
Tth(j-mb) thermal resistance from junction to mounting base see <u>righter</u>	2 K/W	-	-	see Figure 4	thermal resistance from junction to mounting base	R _{th(j-mb)}



PH6325L

N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK

6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	25	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	2.2	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 150 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	0.5	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.5	2	V
I _{DSS}	drain leakage current	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.06	1	μA
		V_{DS} = 25 V; V_{GS} = 0 V; T_j = 150 °C	-	-	500	μΑ
I _{GSS}	gate leakage current	V_{GS} = 16 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
		V_{GS} = -16 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
R_{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 150 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	7.5	10.1	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 150 \text{ °C};$ see Figure 9; see Figure 10	-	11.8	15.2	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	7.4	9.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 9; see Figure 10	-	4.7	6.3	mΩ
		<u>ingulo o</u> , oco <u>ingulo ro</u>				
R _G	internal gate resistance	f = 1 MHz	-	1.8	-	Ω
	internal gate resistance characteristics		-	1.8	-	Ω
	-		-	1.8 13.3	-	Ω nC
Dynamic	characteristics	f = 1 MHz I _D = 25 A; V _{DS} = 12 V; V _{GS} = 4.5 V;	-			
Dynamic	characteristics	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$		13.3	-	nC
Dynamic Q _{G(tot)}	characteristics total gate charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set	-	13.3 11.1	-	nC nC
Dynamic (Q _{G(tot)}	characteristics total gate charge gate-source charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set	-	13.3 11.1 4.9	-	nC nC nC
Dynamic Q _{G(tot)}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set		13.3 11.1 4.9 2.6	-	nC nC nC nC
Dynamic Q _{G(tot)} Q _{GS} Q _{GS1} Q _{GS2}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set		13.3 11.1 4.9 2.6 2.3	-	nC nC nC nC nC
Dynamic Q _{G(tot)} Q _{GS1} Q _{GS2} Q _{GD}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$	- - - -	 13.3 11.1 4.9 2.6 2.3 3.3 	-	nC nC nC nC nC nC
Dynamic Q _{G(tot)} Q _{GS1} Q _{GS2} Q _{GD} V _{GS(pl)}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage	$ \begin{split} f &= 1 \text{ MHz} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ I_D &= 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12; see Figure 12} \\ \\ \\ \\ I_D &= 0 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz; } \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ $	- - - -	13.3 11.1 4.9 2.6 2.3 3.3 2.4	-	nC nC nC nC nC NC V
Dynamic Q _{G(tot)} Q _{GS1} Q _{GS2} Q _{GD} V _{GS(pl)}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage	$ \begin{split} f &= 1 \text{ MHz} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ see Figure 11; see Figure 12 \\ I_D &= 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V} \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ see Figure 11; see Figure 12 \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ See Figure 11}; \\ see Figure 12 \\ \\ \\ \\ V_{DS} &= 0 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz}; \\ \\ \\ \\ T_j &= 25 \text{ °C}; see Figure 13; \\ \\ \end{split} $	- - - -	 13.3 11.1 4.9 2.6 2.3 3.3 2.4 2420 	- - - - - -	nC nC nC nC nC V
Dynamic Q _G (tot) Q _{GS1} Q _{GS2} Q _{GD} V _{GS(pl)} C _{iss}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage input capacitance	$ \begin{split} f &= 1 \text{ MHz} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ I_D &= 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12; see Figure 12} \\ \\ \\ \\ I_D &= 0 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz; } \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ $	- - - - -	13.3 11.1 4.9 2.6 2.3 3.3 2.4 2420 1871	- - - - - - -	nC nC nC nC nC V v
Dynamic Q _G (tot) Q _{GS} Q _{GS1} Q _{GS2} Q _{GD} V _{GS(pl)} C _{iss} C _{oss}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage input capacitance output capacitance	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$ see Figure 12 $V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; \text{ see Figure 13};$ see Figure 14 $V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	- - - - - -	 13.3 11.1 4.9 2.6 2.3 3.3 2.4 2420 1871 517 	- - - - - - -	nC nC nC nC nC V pF pF
Dynamic Q _G (tot) Q _{GS} Q _{GS1} Q _{GS2} Q _{GD} V _{GS} (pl) C _{iss} C _{oss} C _{rss}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage input capacitance output capacitance reverse transfer capacitance	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$ see Figure 12 $V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; \text{ see Figure 13};$ see Figure 14	- - - - - - - -	13.3 11.1 4.9 2.6 2.3 3.3 2.4 2420 1871 517 179	- - - - - - - - - - -	nC nC nC nC nC v pF pF pF
Dynamic Q _G (tot) Q _{GS} Q _{GS1} Q _{GS2} Q _{GD} V _{GS(pl)} C _{iss} C _{oss} C _{rss} t _{d(on)}	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage input capacitance reverse transfer capacitance turn-on delay time	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$ see Figure 12 $V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; \text{ see Figure 13};$ see Figure 14 $V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	- - - - - - - -	 13.3 11.1 4.9 2.6 2.3 3.3 2.4 2420 1871 517 179 25 	- - - - - - - - - -	nC nC nC nC nC V pF pF pF pF ns

Symbol

Source-drain diode

PH6325L

Max

Unit

N-channel 25 V 6.3 m Ω logic level MOSFET in LFPAK

Min

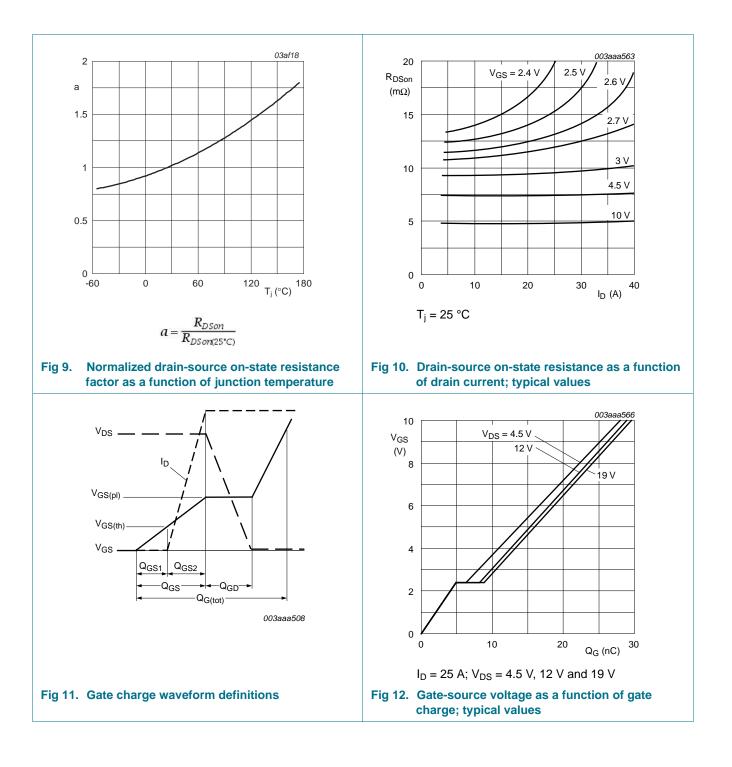
Тур

V _{SD}	source-drain voltage	I _S = 25 A; V _{GS} see <u>Figure 15</u>	= 0 V; T_j = 25 °C;	-	0.85	1.2	V
t _{rr}	reverse recovery time		dt = -100 A/µs;	-	33	-	ns
Qr	recovered charge	$V_{GS} = 0 V; V_{DS}$	_S = 25 V	-	13	-	nC
4 I _D (A) 3	10 V 4.5 V 2.7 V V _C	003aaa561 3S = 2.6 V 2.5 V 2.4 V	40 I _D (A) 30			03aaa562	
2	0	2.3 V 2.2 V 2.1 V	20	T _j = 150 °C	25 °C		
1		2 V 1.8 V 1.6 V	10				
	0 0.5 1 1	.5 _{VDS} (V) ²	0	1		s (V) ³	
Fig 5.	T _j = 25 °C Output characteristics: drain function of drain-source volta		Fig 6. Transfer ch	nd 150 °C; V _D aracteristics gate-source	: drain c	urrent	
2 V _{GS(} (V)	th)	03aa33	10 ⁻¹ I _D (A) 10 ⁻²			3aa36	
1	1 min	```````````````````````````````````````	10 ⁻³	min 1/2 typ 2/2	max		
0	.5		10 ⁻⁵				
	0 -60 0 60 12	20 180 T _j (°C)	10 ⁻⁶ /	1 1	2 V _G	3 3 (V)	
			T _j = 25 °C; ∖	/ _{DS} = 5 V			
	$I_D = 1 m A; V_{DS} = V_G.$	S	,				

Conditions

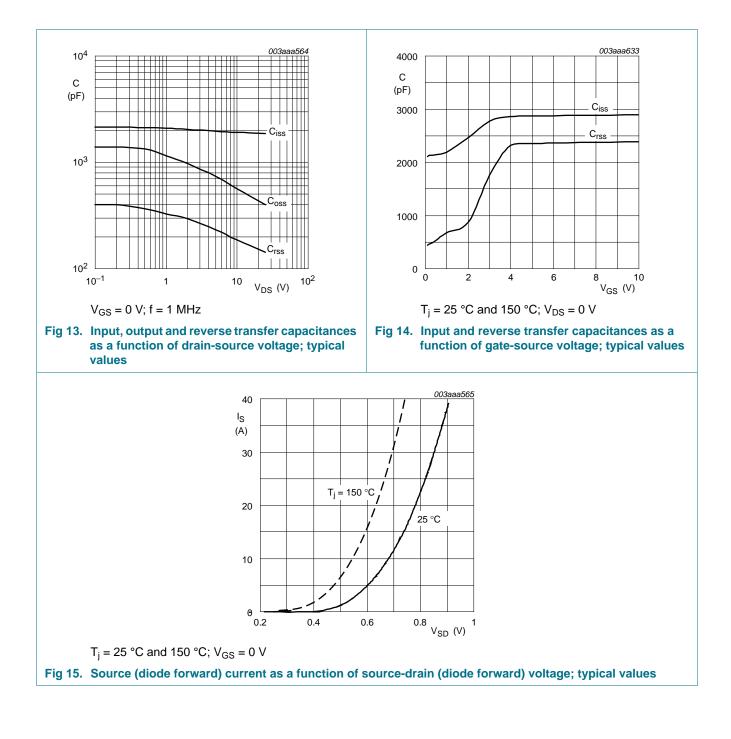
PH6325L

N-channel 25 V 6.3 m Ω logic level MOSFET in LFPAK



PH6325L

N-channel 25 V 6.3 m Ω logic level MOSFET in LFPAK



PH6325L

N-channel 25 V 6.3 m Ω logic level MOSFET in LFPAK

7. Package outline

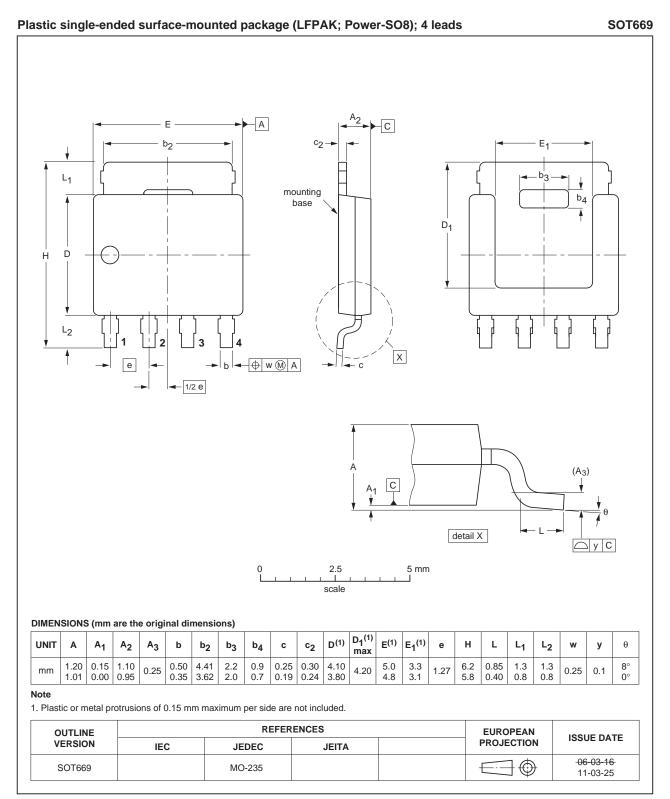


Fig 16. Package outline SOT669 (LFPAK; Power-SO8)

All information provided in this document is subject to legal disclaimers.

8. Revision history

Table 7. Rev	ision history					
Document ID	Release date	Data sheet status	Change notice	Supersedes		
PH6325L v.2	20111222	Product data sheet	-	PH6325L v.1		
Modifications:		 The format of this document has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 				
	 Legal texts have 	ve been adapted to the new	company name where	appropriate.		
	 Status changed 	d from preliminary to produc	t.			
PH6325L v.1	20040428	Preliminary data shee	t -	-		

9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <u>http://www.nxp.com</u>.

9.2 Definitions

Preview — The document is a preview version only. The document is still subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

Product specification — The information and data provided in a Product data sheet shall define the specification of the product as agreed between NXP Semiconductors and its customer, unless NXP Semiconductors and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the NXP Semiconductors product is deemed to offer functions and qualities beyond those described in the Product data sheet.

9.3 Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

In no event shall NXP Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, NXP Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the *Terms and conditions of commercial sale* of NXP Semiconductors.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using NXP Semiconductors products, and NXP Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the NXP Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

NXP Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using NXP Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). NXP does not accept any liability in this respect.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

12 of 14

PH6325L

Terms and conditions of commercial sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <u>http://www.nxp.com/profile/terms</u>, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. NXP Semiconductors hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of NXP Semiconductors products by customer.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

Non-automotive qualified products — Unless this data sheet expressly states that this specific NXP Semiconductors product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. NXP Semiconductors accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

10. Contact information

For more information, please visit: <u>http://www.nxp.com</u>

For sales office addresses, please send an email to: salesaddresses@nxp.com

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without NXP Semiconductors' warranty of the product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond NXP Semiconductors' specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies NXP Semiconductors for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond NXP Semiconductors' standard warranty and NXP Semiconductors' product specifications.

9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

Adelante, Bitport, Bitsound, CoolFlux, CoReUse, DESFire, EZ-HV, FabKey, GreenChip, HiPerSmart, HITAG, I²C-bus logo, ICODE, I-CODE, ITEC, Labelution, MIFARE, MIFARE Plus, MIFARE Ultralight, MoReUse, QLPAK, Silicon Tuner, SiliconMAX, SmartXA, STARplug, TOPFET, TrenchMOS, TriMedia and UCODE — are trademarks of NXP B.V.

HD Radio and HD Radio logo — are trademarks of iBiquity Digital Corporation.

PH6325L

N-channel 25 V 6.3 m Ω logic level MOSFET in LFPAK

11. Contents

1	Product profile1
1.1	General description1
1.2	Features and benefits1
1.3	Applications1
1.4	Quick reference data1
2	Pinning information2
3	Ordering information2
4	Limiting values3
5	Thermal characteristics5
6	Characteristics6
7	Package outline10
8	Revision history11
9	Legal information12
9.1	Data sheet status
9.2	Definitions12
9.3	Disclaimers
9.4	Trademarks
10	Contact information13

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

© NXP B.V. 2011.

All rights reserved.

For more information, please visit: http://www.nxp.com For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 22 December 2011 Document identifier: PH6325L